



WANSEMI
万芯半导体

WP2312AS3

Enhancement Mode N-Channel Power MOSFET

SOT23-3/NMOS/20V/ ± 12 V/0.7V/6.8A/14m Ω

Rev0.6

20V, 14mΩ, 6.8A, Single N-Channel

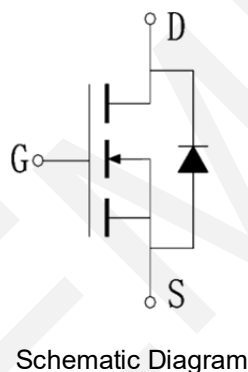
1.Features

- ◆ 20V MOSFET technology
- ◆ Low on-state resistance
- ◆ Fast switching
- ◆ $V_{GS} \pm 12V$

V_{DS}	$R_{DS(on)}$ Typ.	I_D Max.
20V	14mΩ @ 4.5V	6.8A
	17mΩ @ 2.5V	

2.Applications

- ◆ Power Switching Application
- ◆ Load Switching



3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP2312AS3	2312A	SOT23-3	3,000	180,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	20	V
Gate to Source Voltage	V_{GSS}	± 12	V
Drain Current (DC)	I_D	6.8	A
Drain Current (Pulse), $PW \leq 300\mu s$	I_{DP}	27	A
Total Dissipation	P_D	1.3	W
Junction Temperature	T_j	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected

5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	97	$^{\circ}C/W$

Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

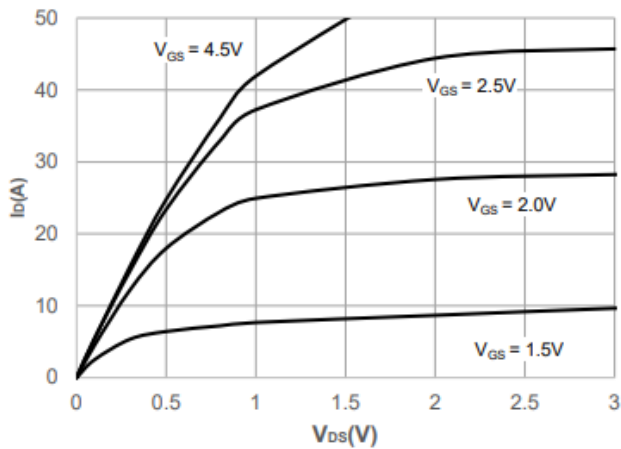
6. Electrical Characteristics at $T_a=25^{\circ}C$ (Note 3)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu A, V_{GS} = 0V$	20	22.5	-	V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$	-	-	1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0V$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	0.5	0.7	1.0	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 4A, V_{GS} = 4.5V$	-	14	21	m Ω
		$I_D = 3A, V_{GS} = 2.5V$	-	17	28	m Ω
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=10V,$ Frequency=1.0MHz		712		pF
Output Capacitance	C_{oss}			116		pF
Reverse Transfer Capacitance	C_{rss}			103		pF
Turn-ON Delay Time	$t_{d(on)}$	$V_{DD} = 10V, I_D=6A$ $V_{GEN} = 4.5V, R_G = 6\Omega$		5		ns
Rise Time	t_r			16		ns
Turn-OFF Delay Time	$t_{d(off)}$			23		ns
Fall Time	t_f			7		ns
Total Gate Charge	Q_g	$V_{DS} = 10V,$ $V_{GS} = 4.5V,$ $I_D = 6A$		9		nC
	Q_{gs}			1.5		nC
	Q_{gd}			2.5		nC
Diode Forward Voltage	V_{FSD}	$I_D = 6.8A, V_{GS} = 0$	0.5	0.85	1.1	V

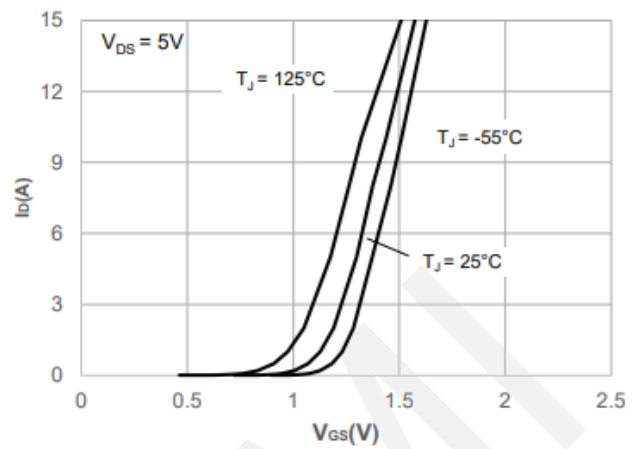
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



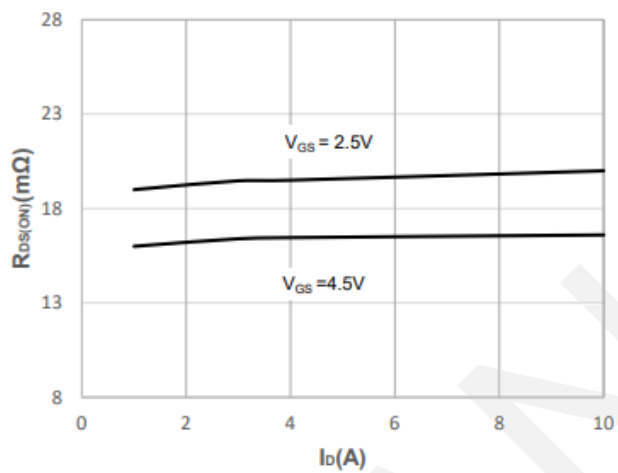
7. Typical electrical and thermal characteristics



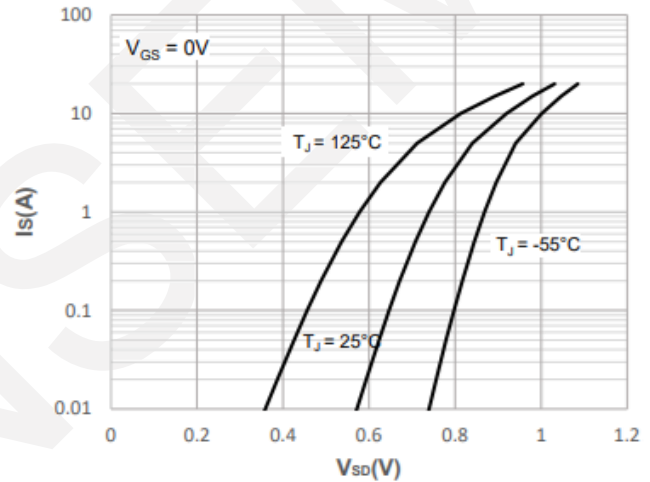
Output Characteristics



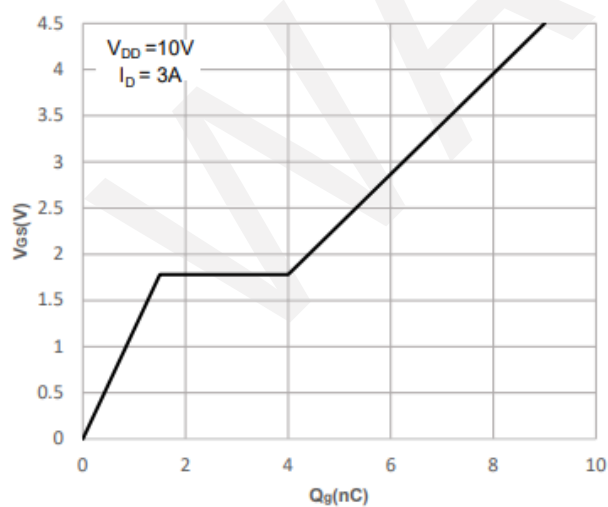
Typical Transfer Characteristics



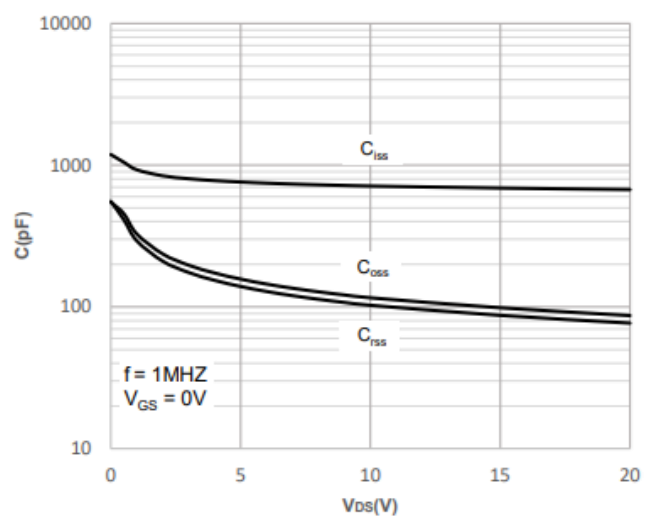
On-resistance vs. Drain Current



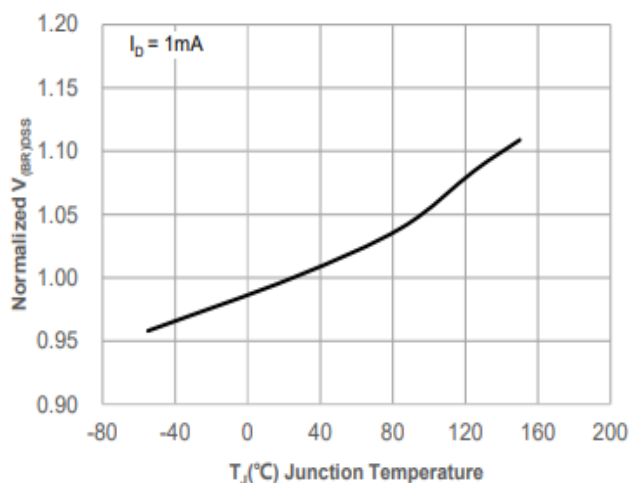
Body Diode Characteristics



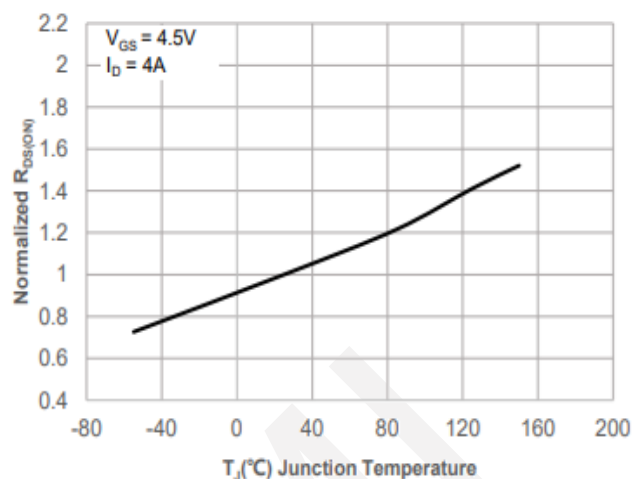
Gate Charge Characteristics



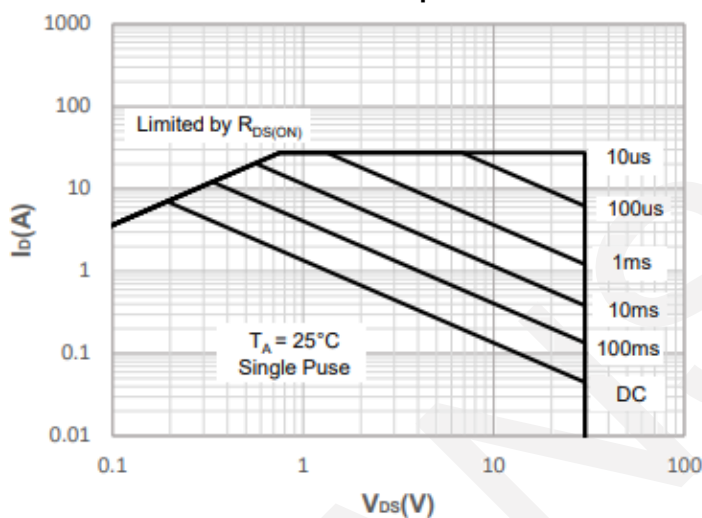
Capacitance Characteristics



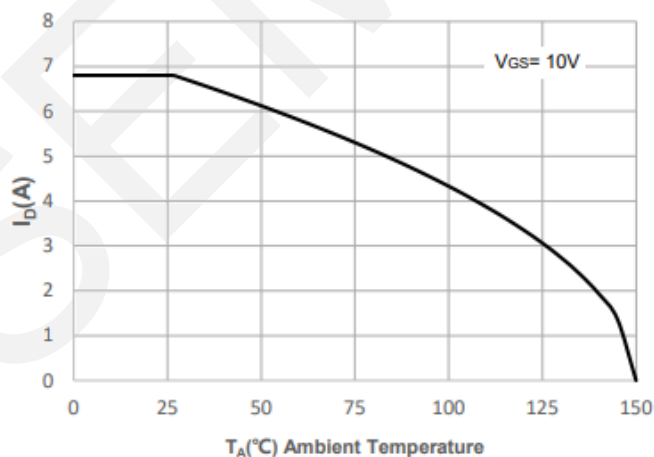
Normalized Breakdown voltage vs. Junction Temperature



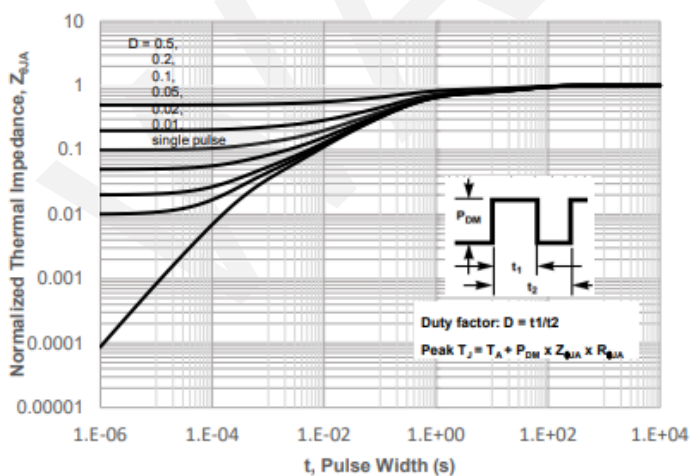
Normalized on Resistance vs. Junction Temperature



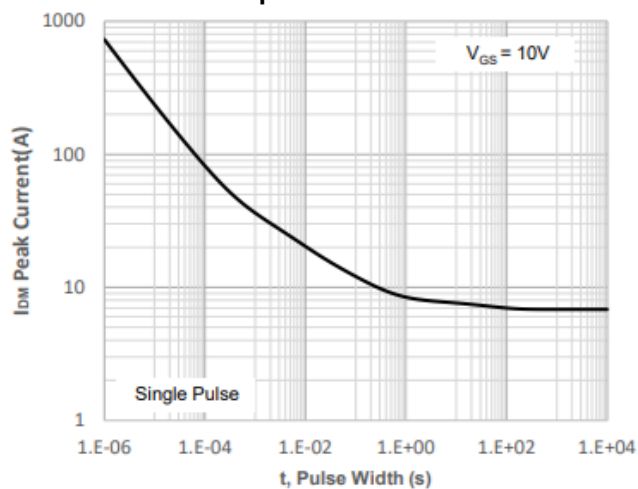
Maximum Safe Operating Area



Maximum Continuous Drian Current vs. Ambient Temperature

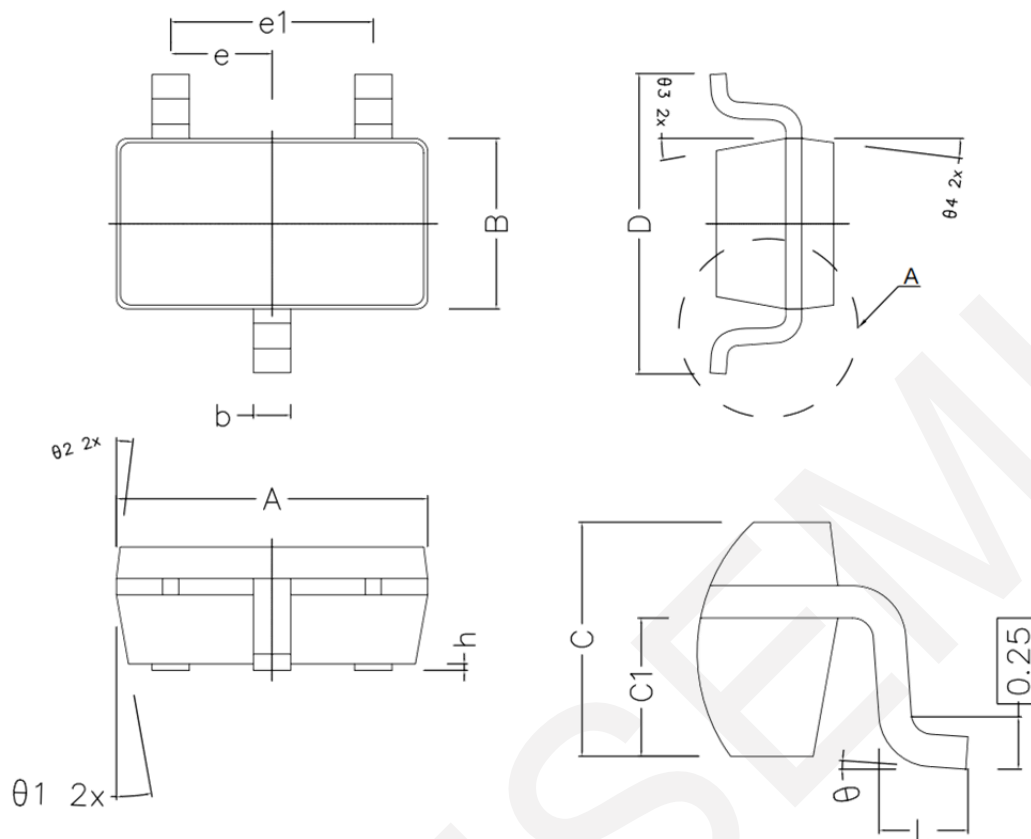


Normalized Maximum Transient Thermal Impedance



Peak Current Capacity

8.Package Dimensions



COMMON DIMENSIONS (UNITS OF MEASURE IS mm)			
	MIN	NORMAL	MAX
A	2.820	2.920	3.020
B	1.500	1.600	1.700
C	1.050	1.100	1.150
C1	0.600	0.650	0.700
D	2.650	2.800	2.950
L	0.300	0.450	0.600
b	0.280	0.350	0.420
h	0.020	0.050	0.100
e	0.950TYPE		
e1	1.900TYPE		
θ ₁	10° TYPE		
θ ₂	7° TYPE		
θ ₃	10° TYPE		
θ ₄	7° TYPE		
θ	0° ~ 8°		

9. Important Notice

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